Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/879,806	HIETALA, ALEX WAYNE	
Examiner	Art Unit	
Jason M. Perilla	2638	

SEARCHED				
Class	Subclass	Date	Examiner	
375	295	8/5/2005	JP	
	296	8/5/2005	JP	
	302	8/5/2005	JP	
	303	8/5/2005	JP	
_	308	8/5/2005	JP	
	306	8/5/2005	JP	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
375	295	8/5/2005	JP	
	302	8/5/2005	JP	
	309	8/5/2005	JP	

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
East USPAT/USPGPUB EPO/JPO	8/5/2005	JP
Inventor Name Search EDAN/EAST	8/5/2005	JP